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(12) United States Design Patent
Kawai

(10) **Patent No.: US D719,861 S**
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(54) **MASS ANALYZER**

(71) Applicant: **Shimadzu Corporation**, Kyoto (JP)

(72) Inventor: **Jun Kawai**, Kyoto (JP)

(73) Assignee: **Shimadzu Corporation**, Kyoto (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/471,610**

(22) Filed: **Nov. 4, 2013**

(30) **Foreign Application Priority Data**

Aug. 19, 2013 (JP) 2013-018829

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/81**; D24/232

(58) **Field of Classification Search**
CPC G05F 7/00; G05F 1/52; G01N 27/62; G01N 27/624; H01J 49/04; H01J 49/26; H01J 49/425; H01J 49/061; H01J 49/0031; H01J 49/49; H01J 49/062; H01J 49/40; H01J 49/408; H01J 49/107; H01J 49/0036; H01J 49/4245; H01J 49/004
USPC D10/81; D24/216, 232, 234
See application file for complete search history.

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Primary Examiner — Antoine D Davis
(74) *Attorney, Agent, or Firm* — Jianq Chyun IP Office

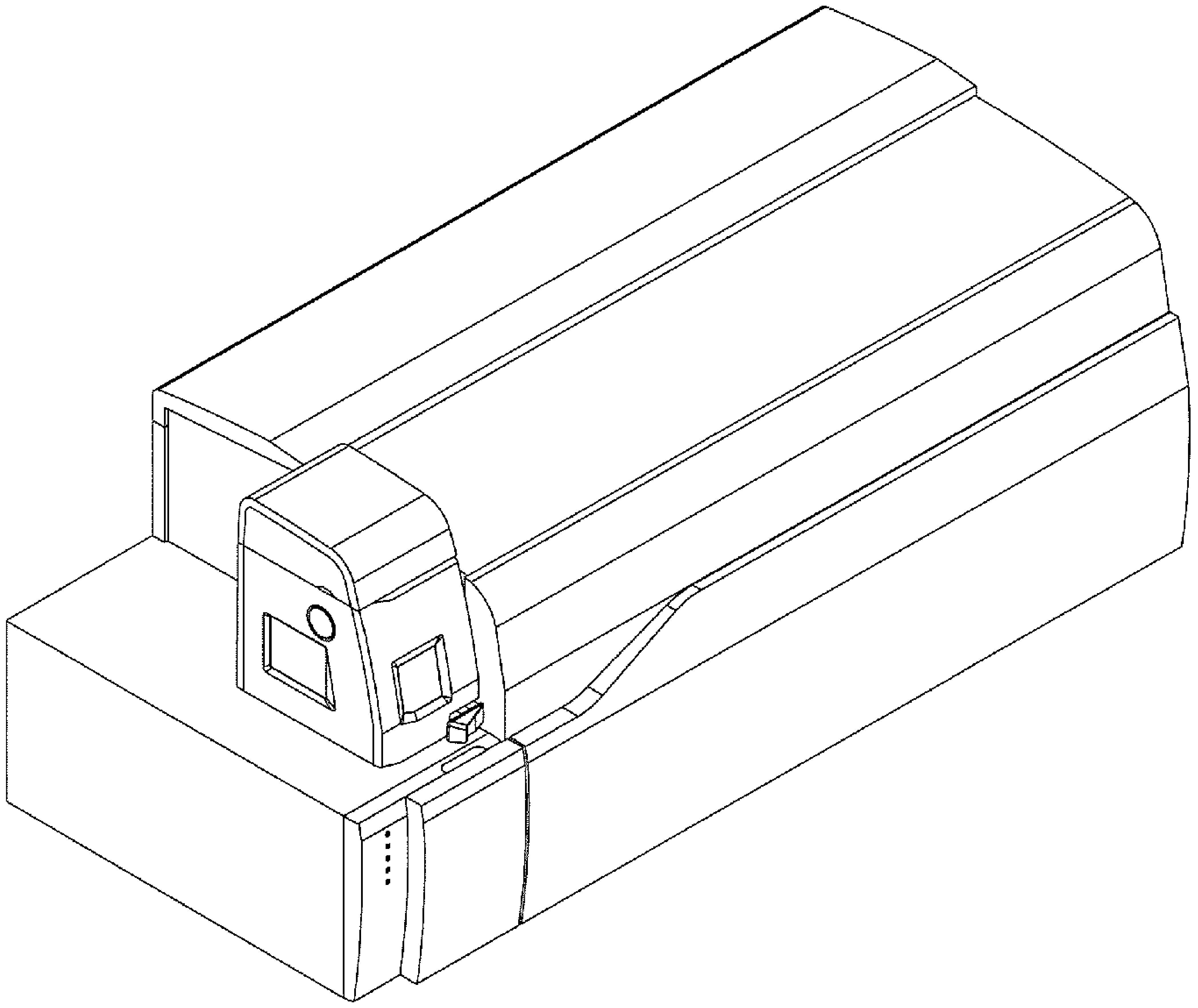
(57) **CLAIM**

The ornamental design for a mass analyzer, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a mass analyzer showing my new design;
FIG. **2** is another perspective view thereof;
FIG. **3** is a front view thereof;
FIG. **4** is a rear view thereof;
FIG. **5** is a left side view thereof;
FIG. **6** is a right side view thereof;
FIG. **7** is a top view thereof; and,
FIG. **8** is a bottom view thereof.

1 Claim, 5 Drawing Sheets



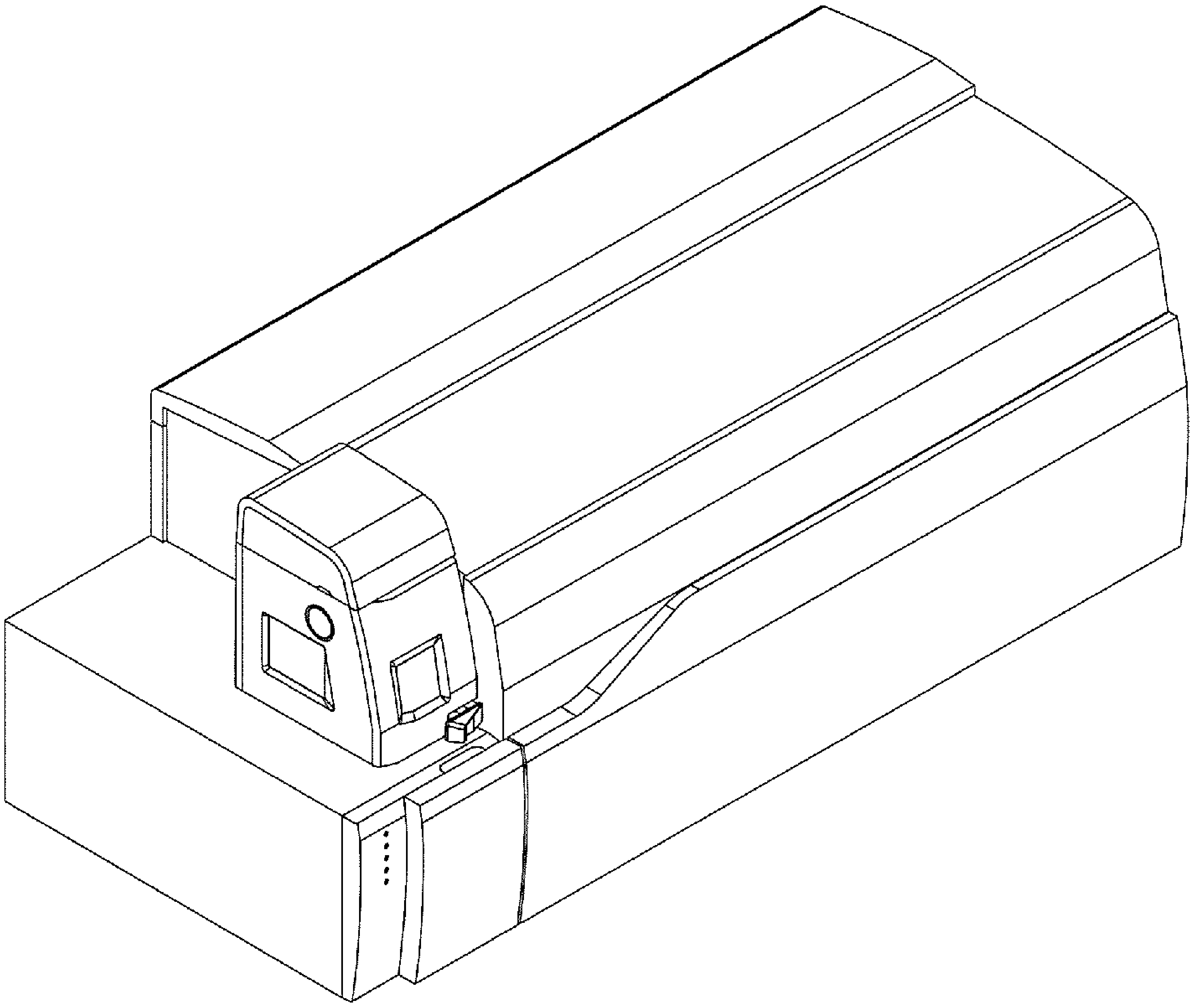


FIG. 1

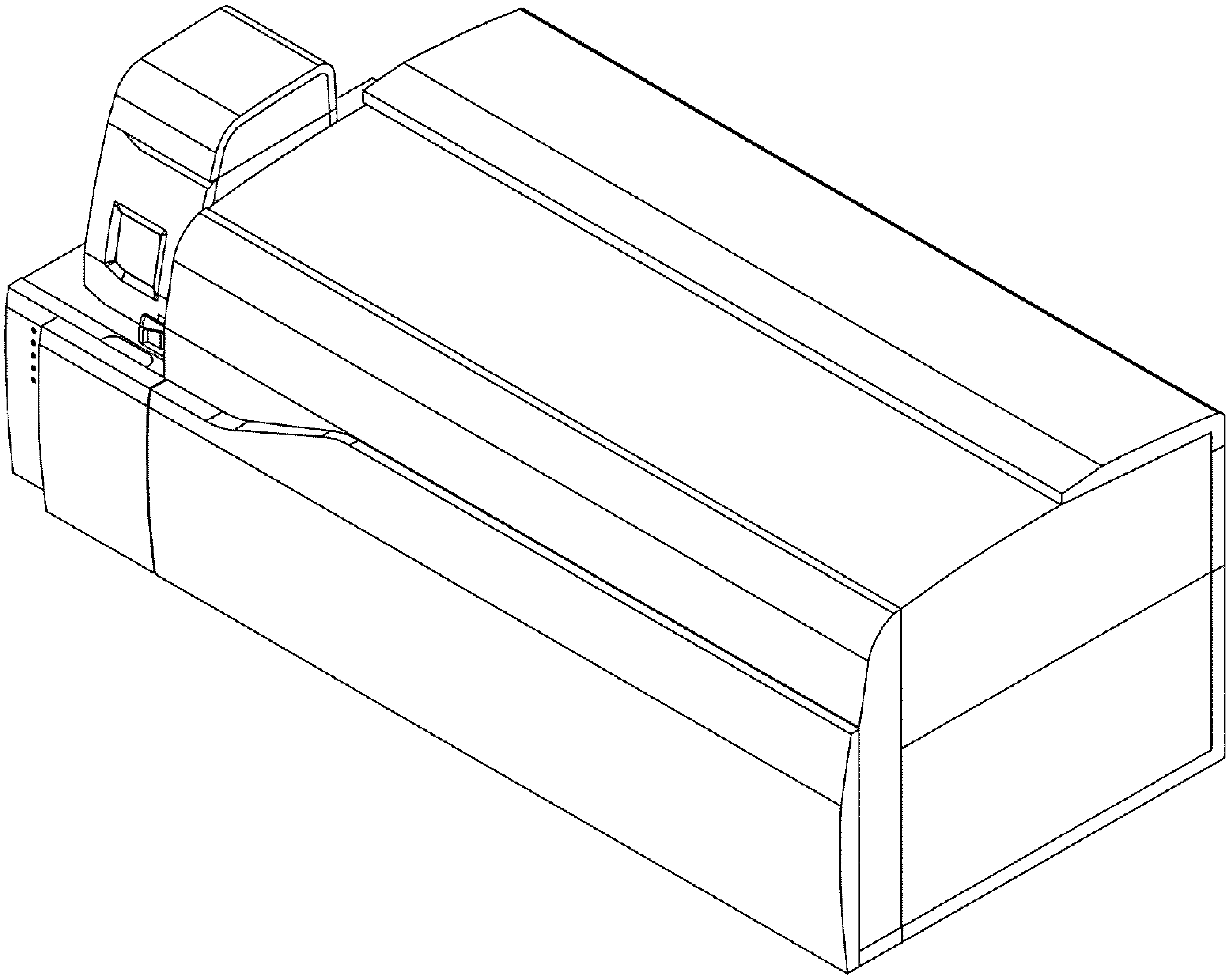


FIG. 2

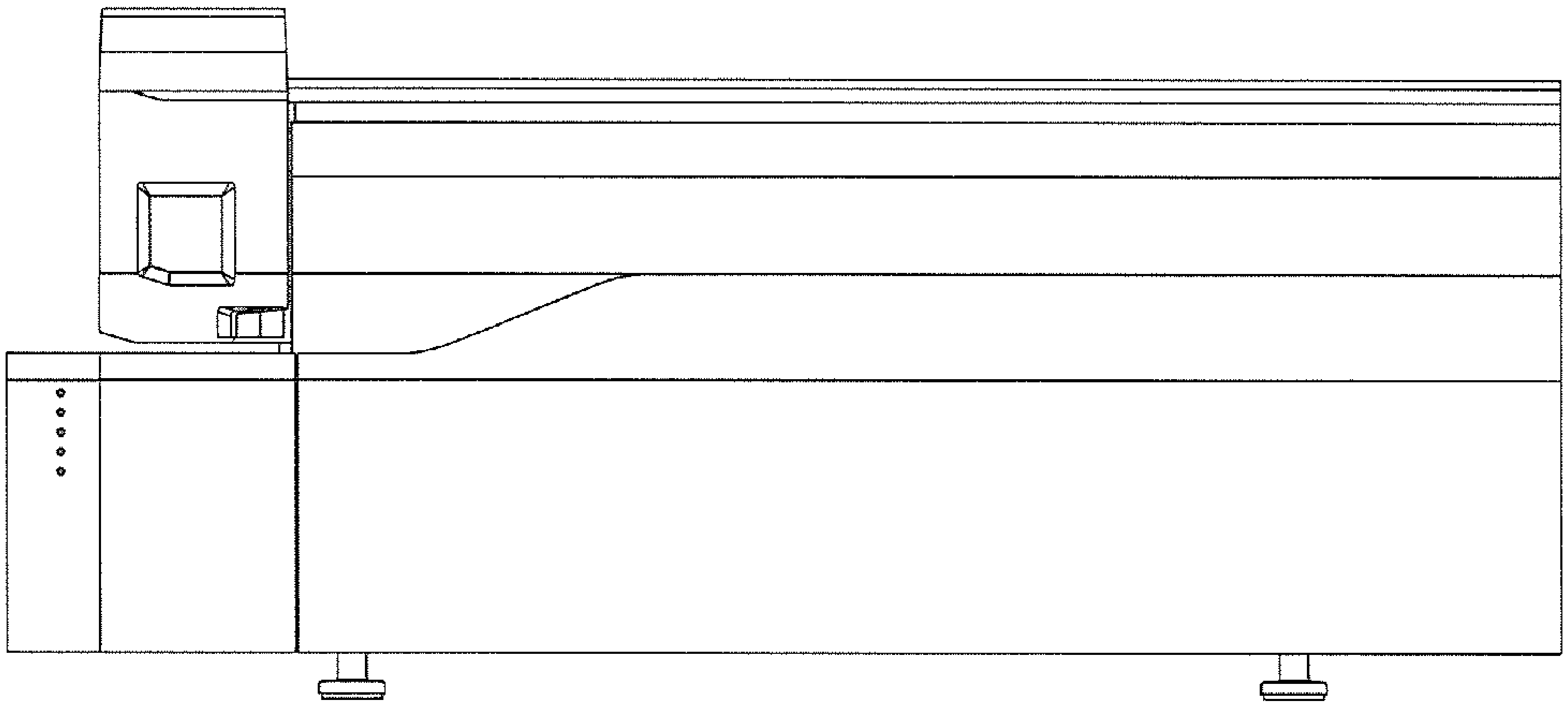


FIG. 3

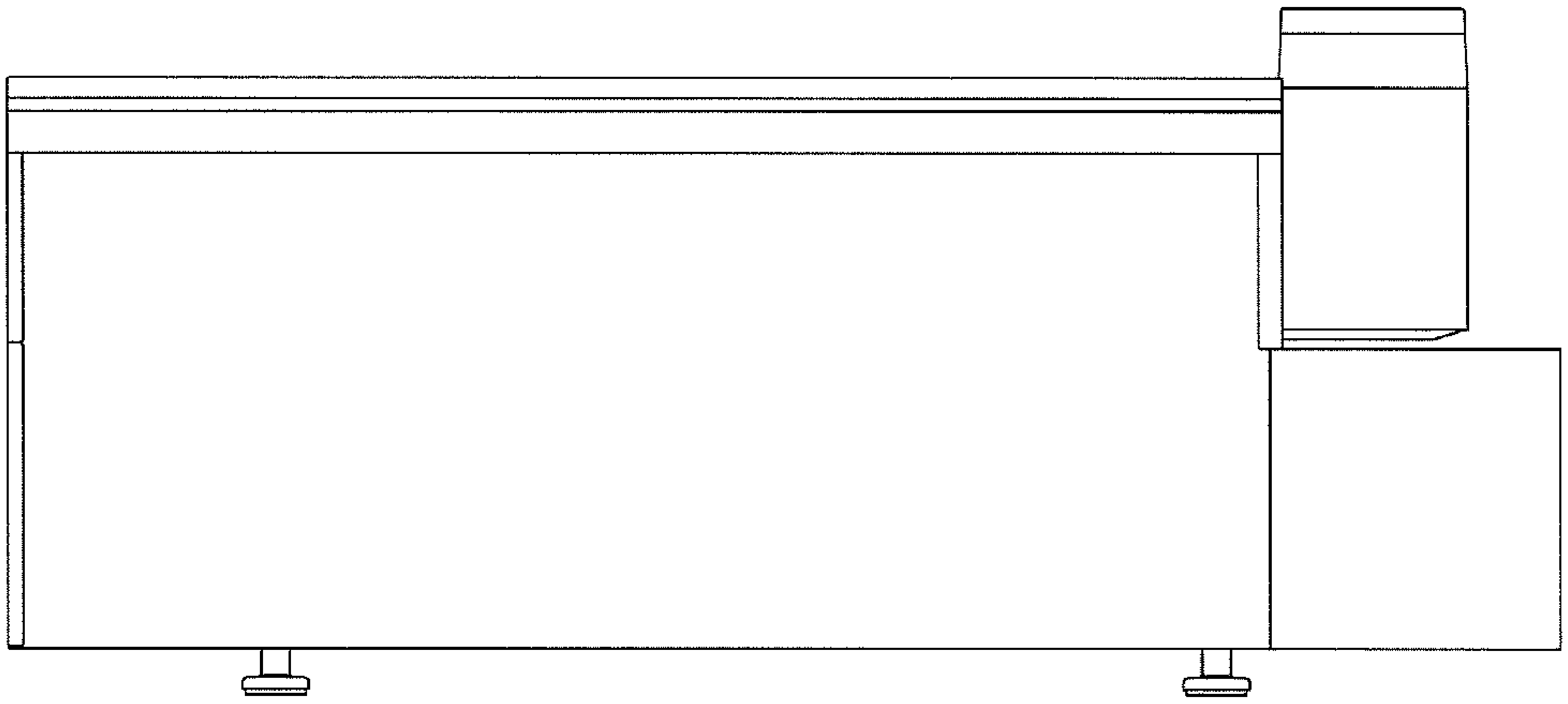


FIG. 4

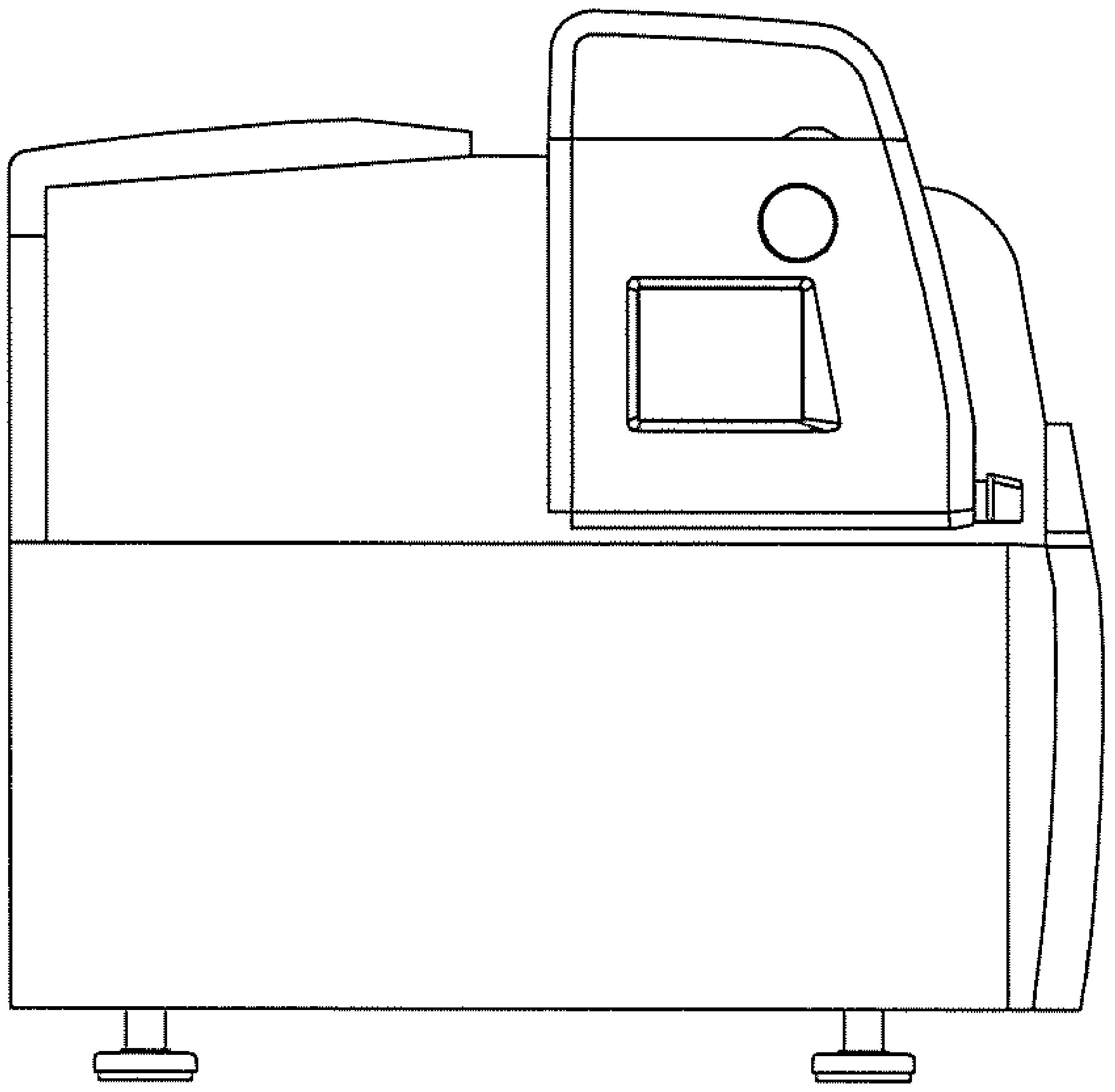


FIG. 5

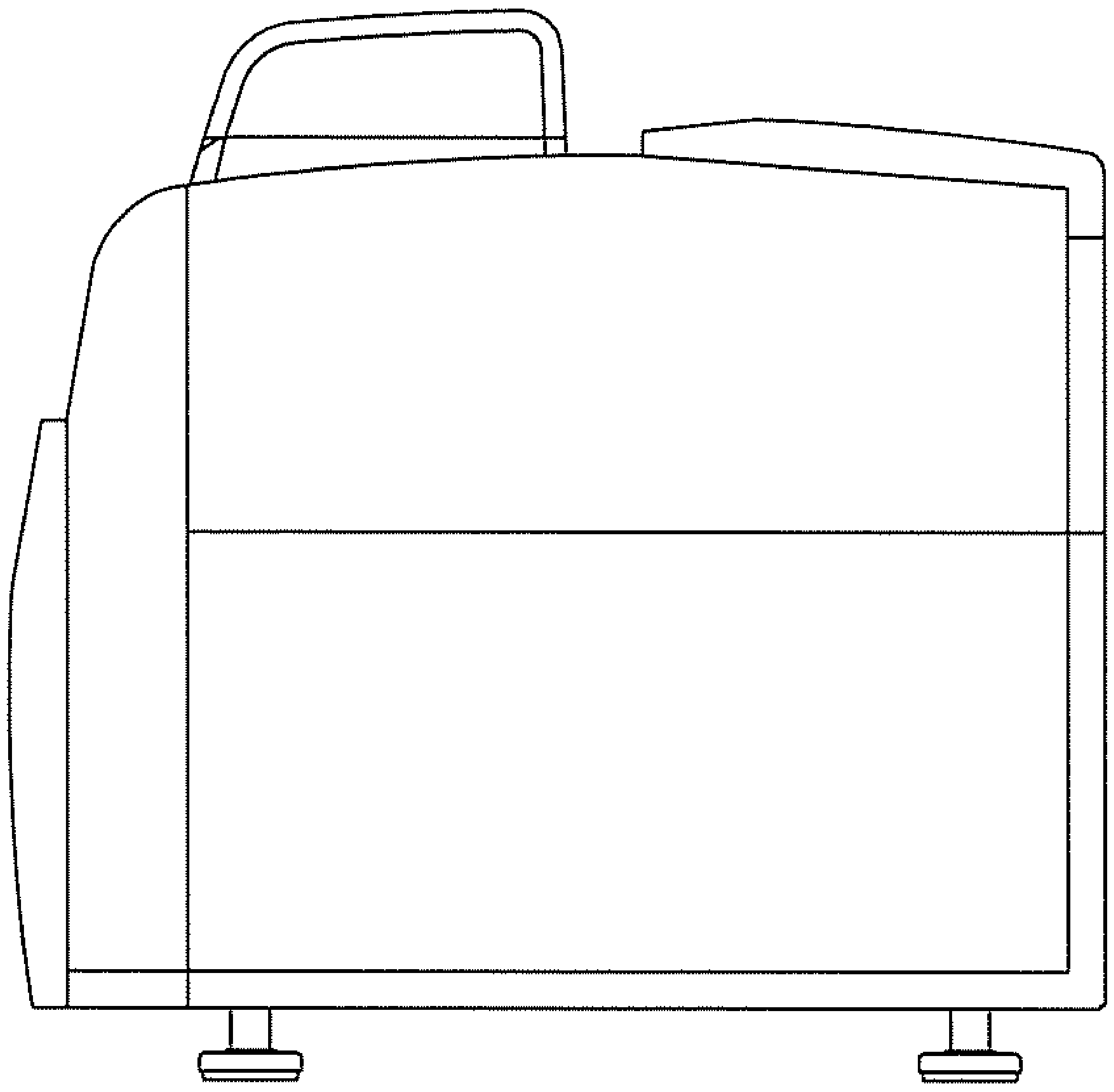


FIG. 6

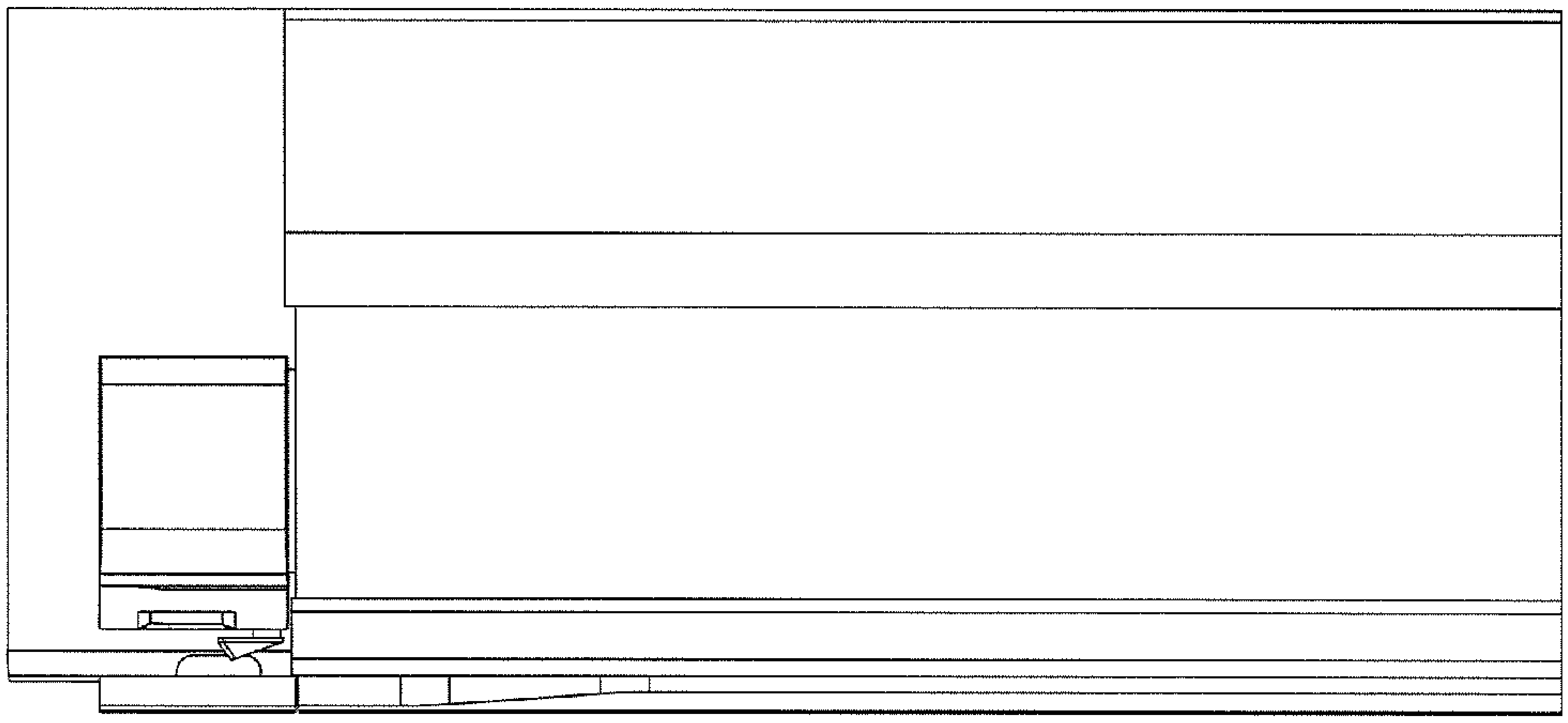


FIG. 7

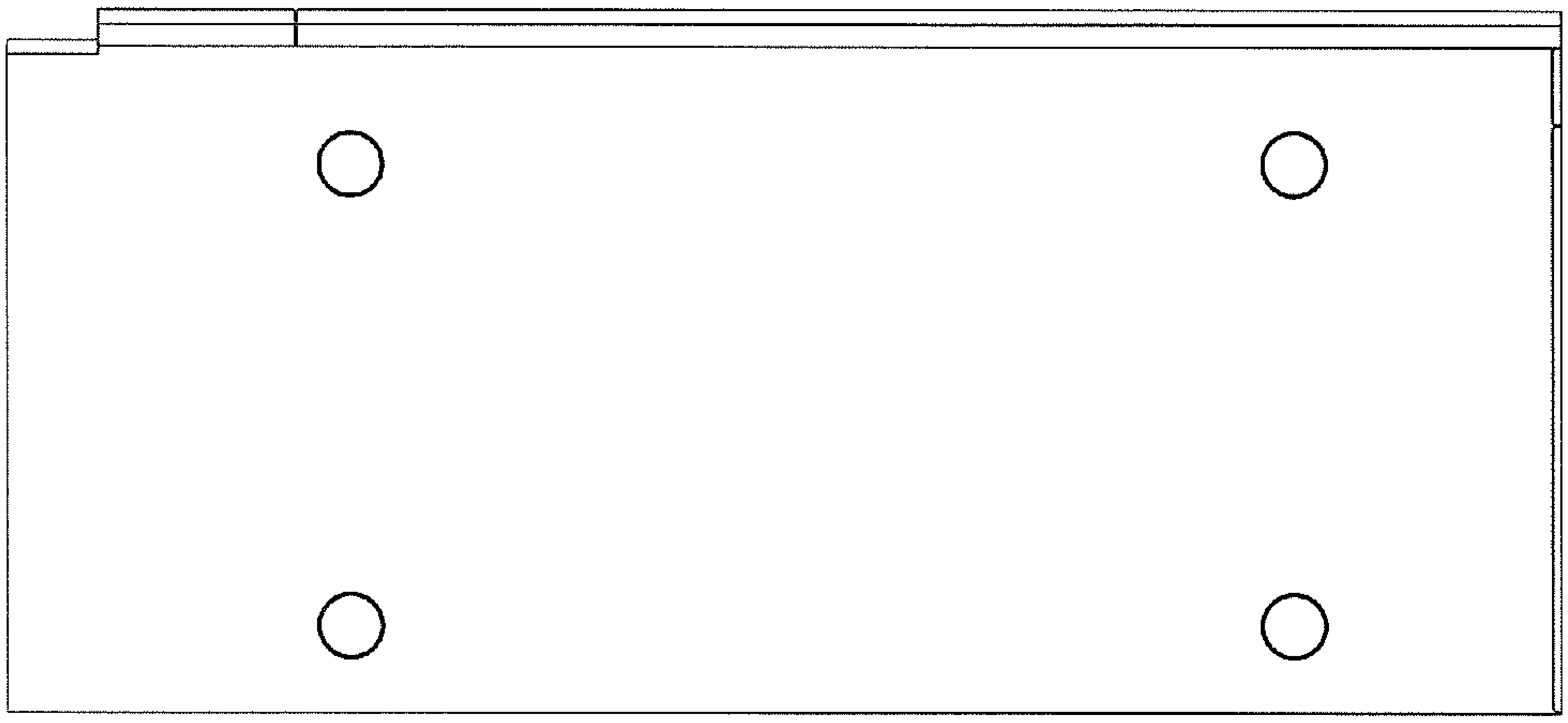


FIG. 8